

**Notice of References Cited**

Application/Control No.

10/511,215

Applicant(s)/Patent Under  
Reexamination  
VAN DE HEUVEL ET AL.

Examiner

Mamon Obeid

Art Unit

3621

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0170053 A1	11-2002	Peterka et al.	725/31
*	B	US-2002/0000156 A1	01-2002	Nishimoto et al.	84/609
	C	US-			
	D	US-			
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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